MI22-2379

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.	
riling Date	10/032,2/3
Inventor	
Assignee	vvarren IVI. Farnworth et al
Group Art Unit	
Examiner	2829
Attorney's Docket No.	Russell M. Kobert
Customer No.	Ml22-2379
	MI22-2379 021567

Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

RESPONSE TO JUNE 6, 2005 OFFICE ACTION

To:

Mail Stop Amendment Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

From:

D. Brent Kenady

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Wells St. John P.S.

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Responsive to the June 6, 2005 Office Action, Applicant amends and remarks as follows:

AMENDMENTS

<u>Underlines</u> indicate insertions and strikeouts indicate deletions.

10/13/2005 BABRAHA1 00000010 10632273

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